

---

## JLab-ILC Polarized e-Source R&D

P. Adderley, J. Brittian, J. Clark, J. Grames, J. Hansknecht,  
M. Poelker, M. Stutzman, R. Suleiman

Students: A. Jayaprakash , J. McCarter, K. Surles-Law

# ILC – unique polarized e-beam requirements

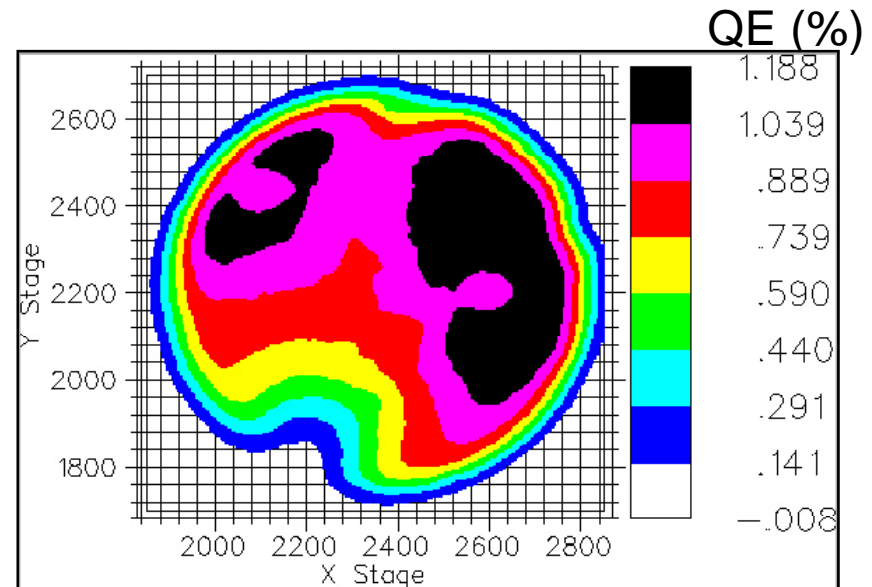
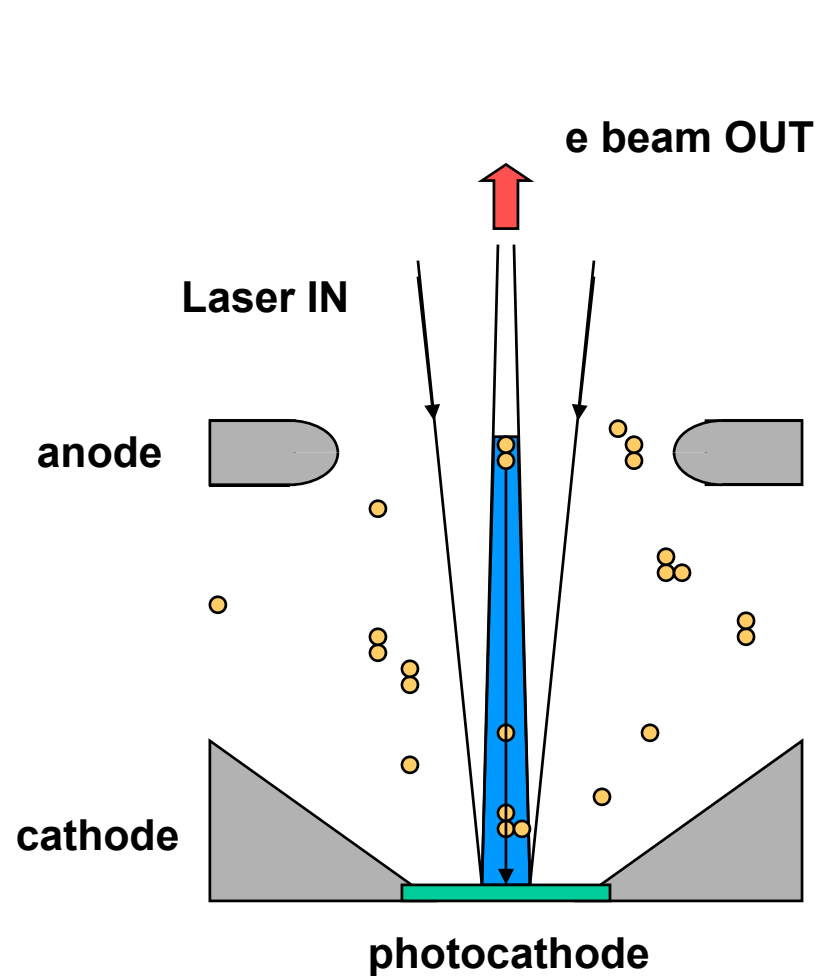
---

- High Average Current (100uA, ~ 50x SLC ave. beam current)
- High Bunch Charge
- Demanding Time Structure

## JLab Expertise

- CEBAF: 10 years experience delivering 100+uA
- Leverage time/money spent building a new CEBAF load locked gun, many features well suited for ILC: improved vacuum, multiple photocathode samples, rapid photocathode replacement

# What limits photogun lifetime?



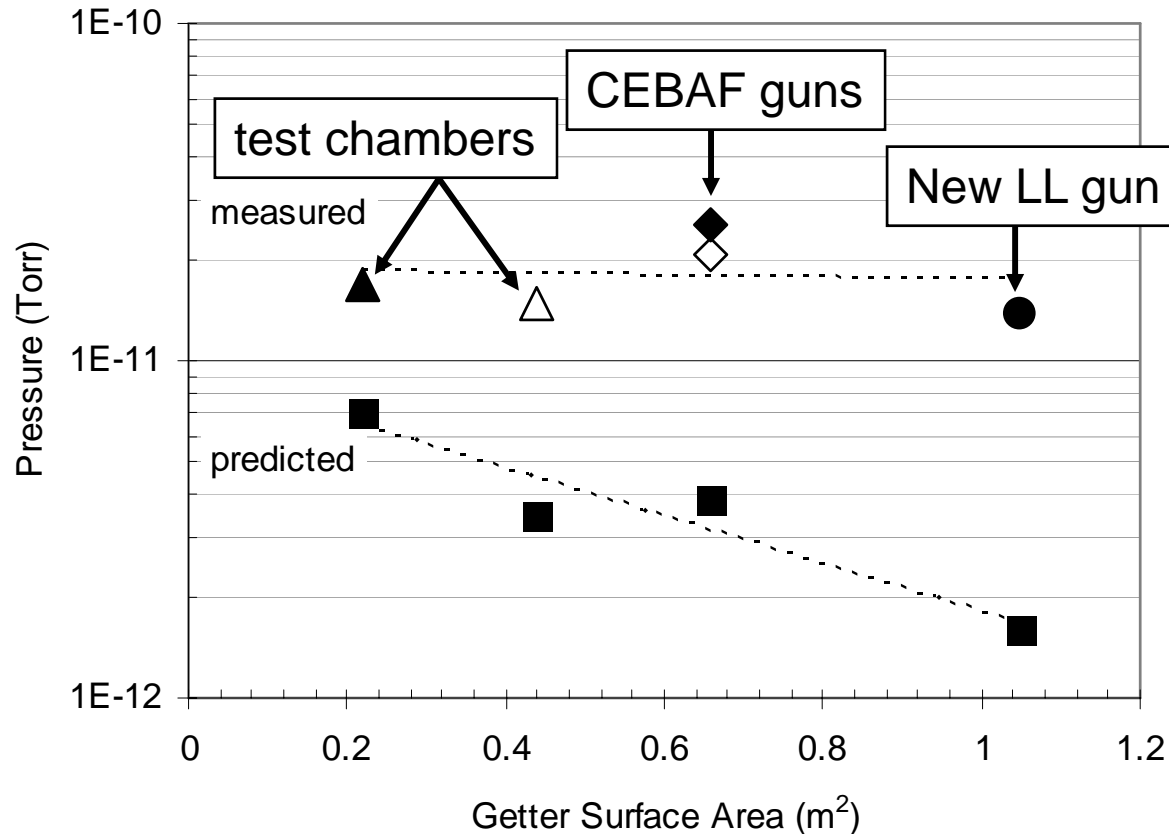
QE scan of photocathode

## Proposed R&D for ILC:

- Vacuum Studies
- High Voltage > 200kV
- Cathode/Anode Design

# Topic #1: Improving Gun Vacuum

$$\text{Ultimate Pressure} = \frac{\text{Outgassing Rate} \times \text{Surface Area}}{\text{Pump Speed}}$$

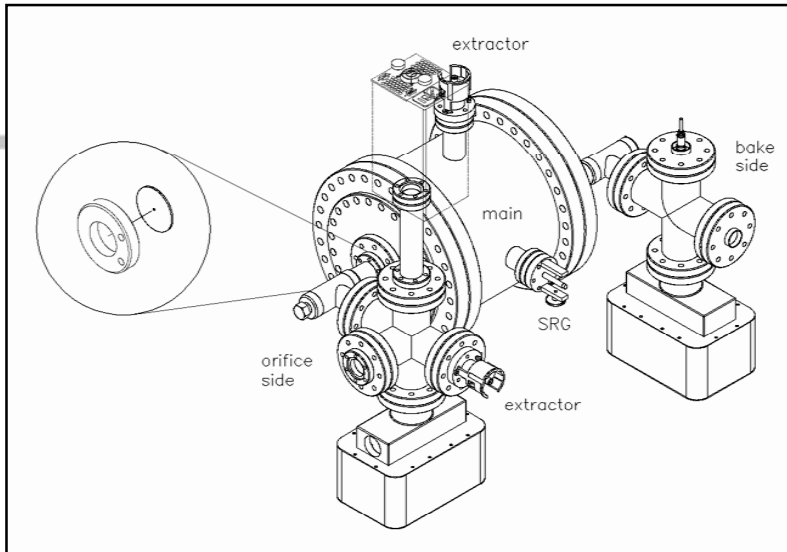


How to explain this discrepancy?

- Outgassing rate higher than assumed “standard” value;  $1 \times 10^{-12}$  Torr·L/s·cm<sup>2</sup>?
- NEG pump speed smaller than SAES says?

Measured pressure always much greater than predicted

# Outgassing Rate

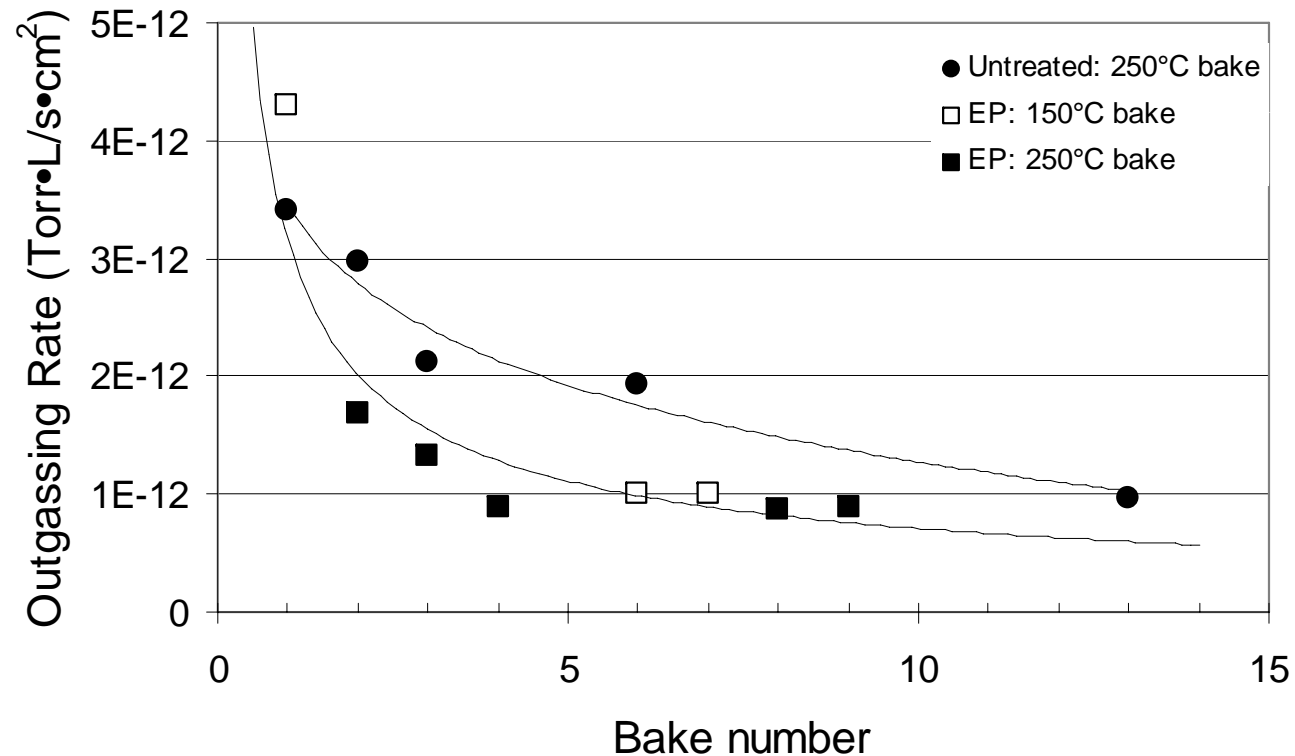


- Orifice and Rate of Rise Methods
- Studied 304, 316L and 6061 Al
- Degreasing/solvent cleaning vs electro-polishing/vacuum firing at 900C

| Chamber | Preprocessing |       |     |                   | In situ bake parameters |         | Outgassing Rate (Torr·L/s·cm <sup>2</sup> ) |                       |
|---------|---------------|-------|-----|-------------------|-------------------------|---------|---|-----------------------|
|         | t(h)          | T(°C) | EP  | Surface roughness | t(h)                    | T(°C)   | Orifice Method                              | Rate of Rise Method   |
| Old 304 |               |       | no  | 3.7 µm            | 400                     | 250     | 9.7x10 <sup>-13</sup>                       | 1x10 <sup>-12</sup>   |
| New 304 |               |       | no  | 3.7 µm            | 180                     | 250     | 1.9x10 <sup>-12</sup>                       | 2.5x10 <sup>-12</sup> |
| EP 304  | 4             | 900   | yes | 2.1 µm            | 30 then 90              | 150 250 |   | 8.9x10 <sup>-13</sup> |

“Characterization of the CEBAF 100 kV DC GaAs Photoelectron Gun Vacuum System,” M.L. Stutzman, et al., Nucl. Instrum. Meth. A, 574 (2007) p. 213-:

# Benefit of EP and Vacuum Firing

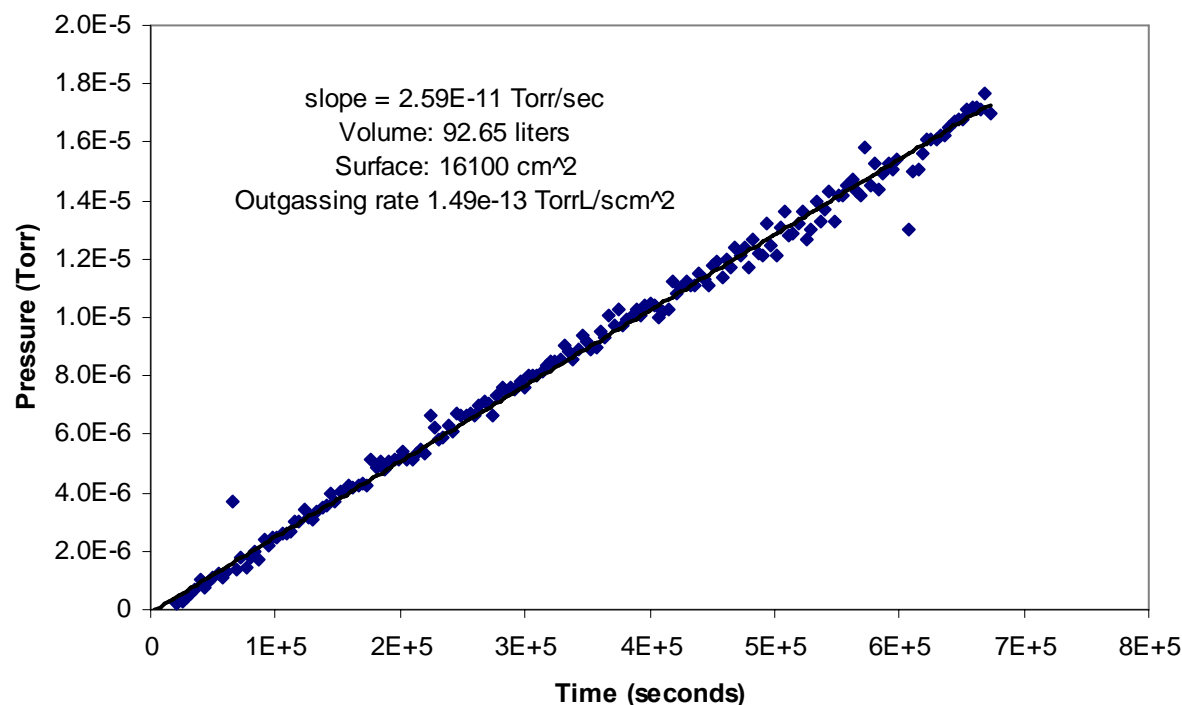


- Electropolishing and vacuum firing provides low rate with fewer bakes
- Extremely low values (e.g.,  $10^{-14}$  to  $10^{-15}$ ) reported in literature elude us
- **Conclusion: We have the “industry-standard” outgassing rate  $\sim 1 \times 10^{-12}$  Torr·L/s·cm<sup>2</sup>**

# Recent High Temperature Bake of JLab FEL Gun

316 LN Stainless Steel, Baked at 400°C for 10 days  
Vacuum inside, hot air outside, Strip heaters instead of hot air guns  
Outgassing rate:  $1.49 \times 10^{-13}$  Torr L/s cm<sup>2</sup>

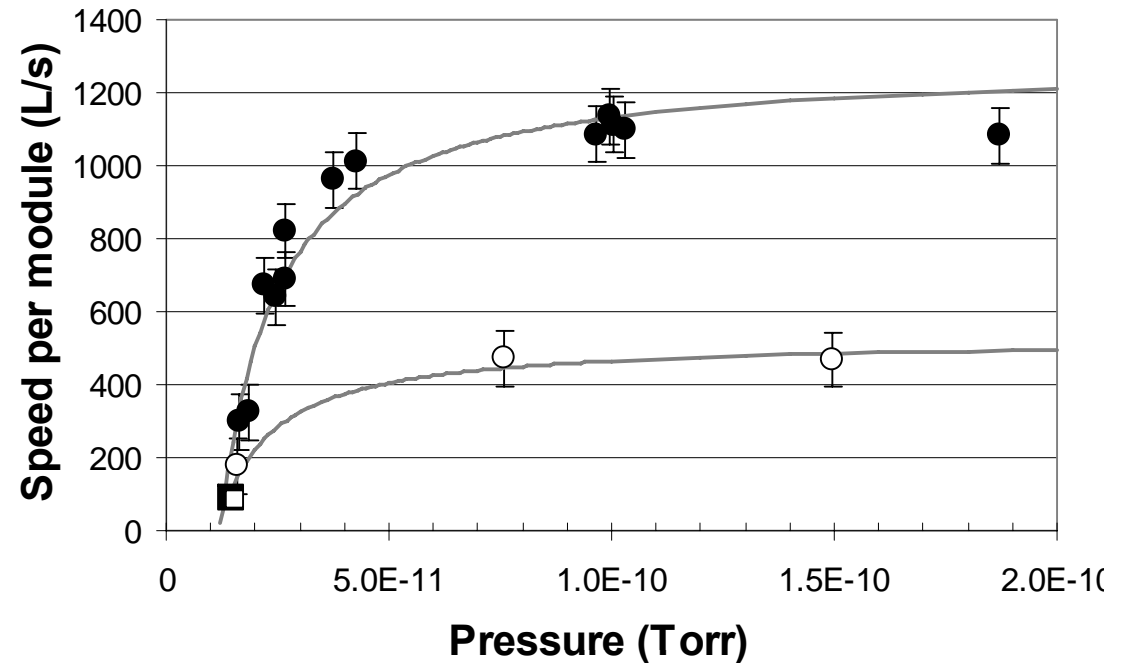
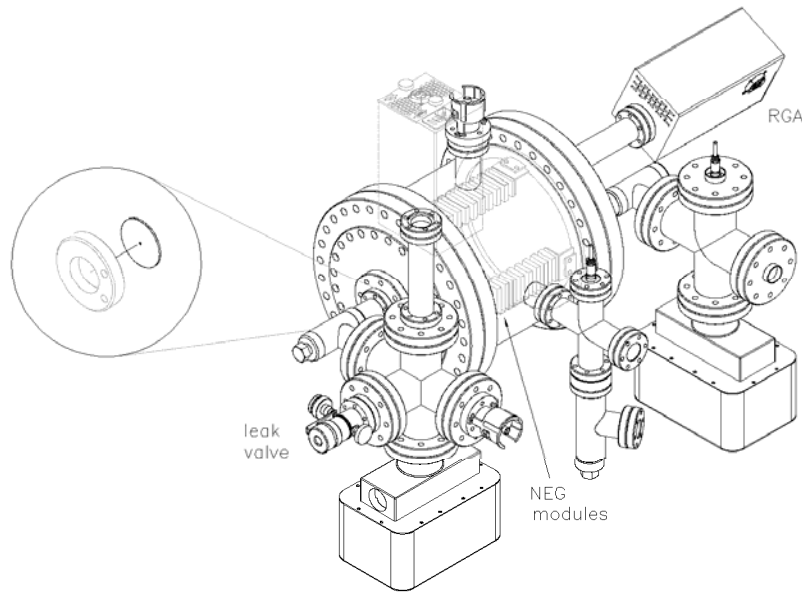
FEL Gun Outgassing Measurement



## Lessons for CEBAF/ILC?

- We should have vacuum fired our end flanges
- Welding introduces hydrogen
- 250C for 30 hours not adequate

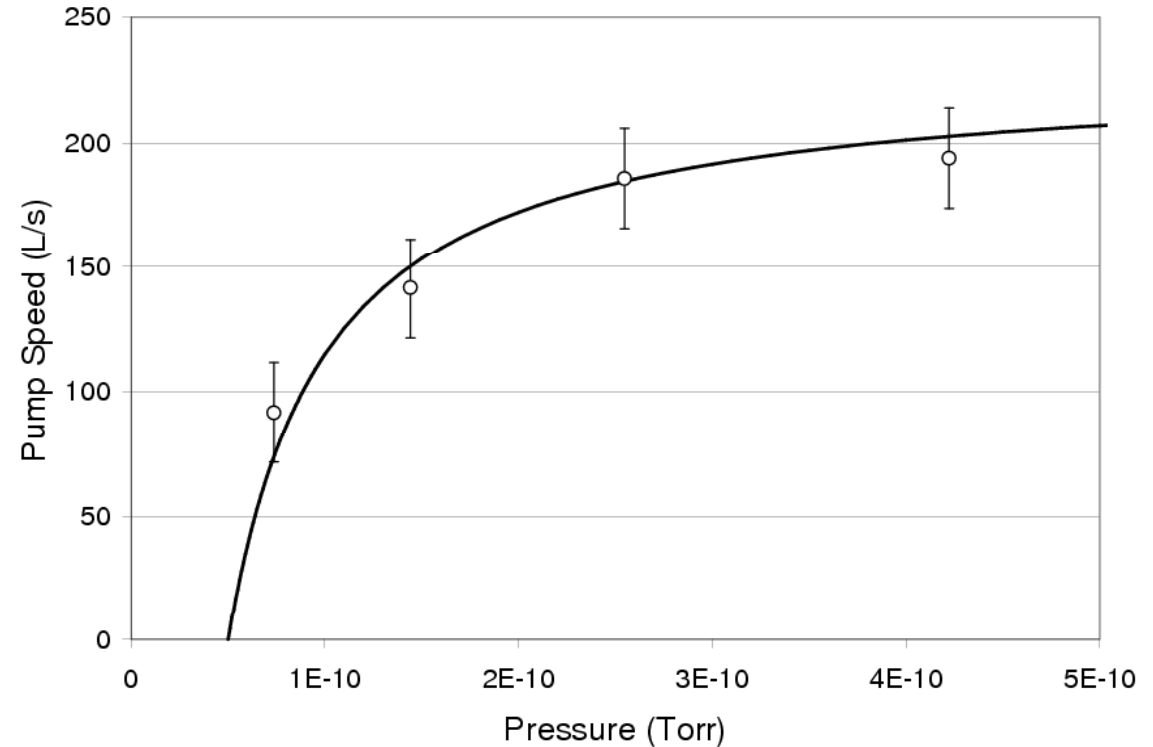
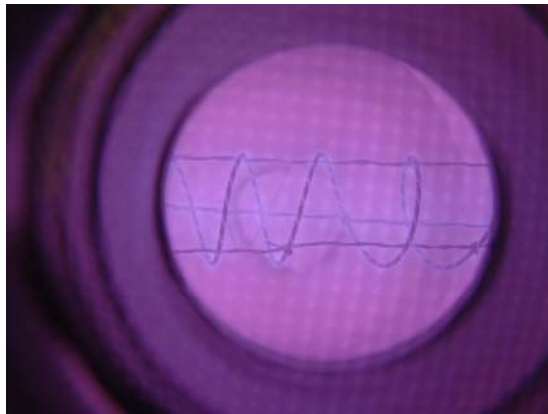
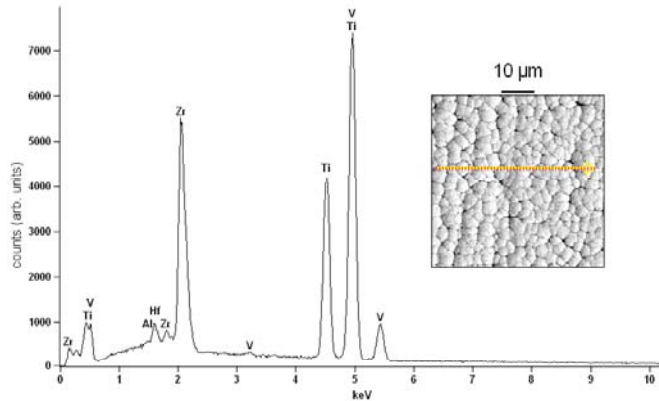
# NEG Pump Speed



- Full NEG activation better than passive activation via bake
- NEG pump speed very good, at least at high pressure
- **Conclusion: Can't explain reduced pump speed at low pressure – a real effect? More likely an indication of gauge limitations**

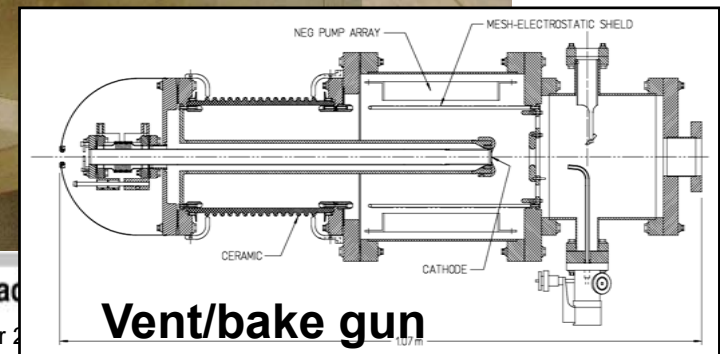
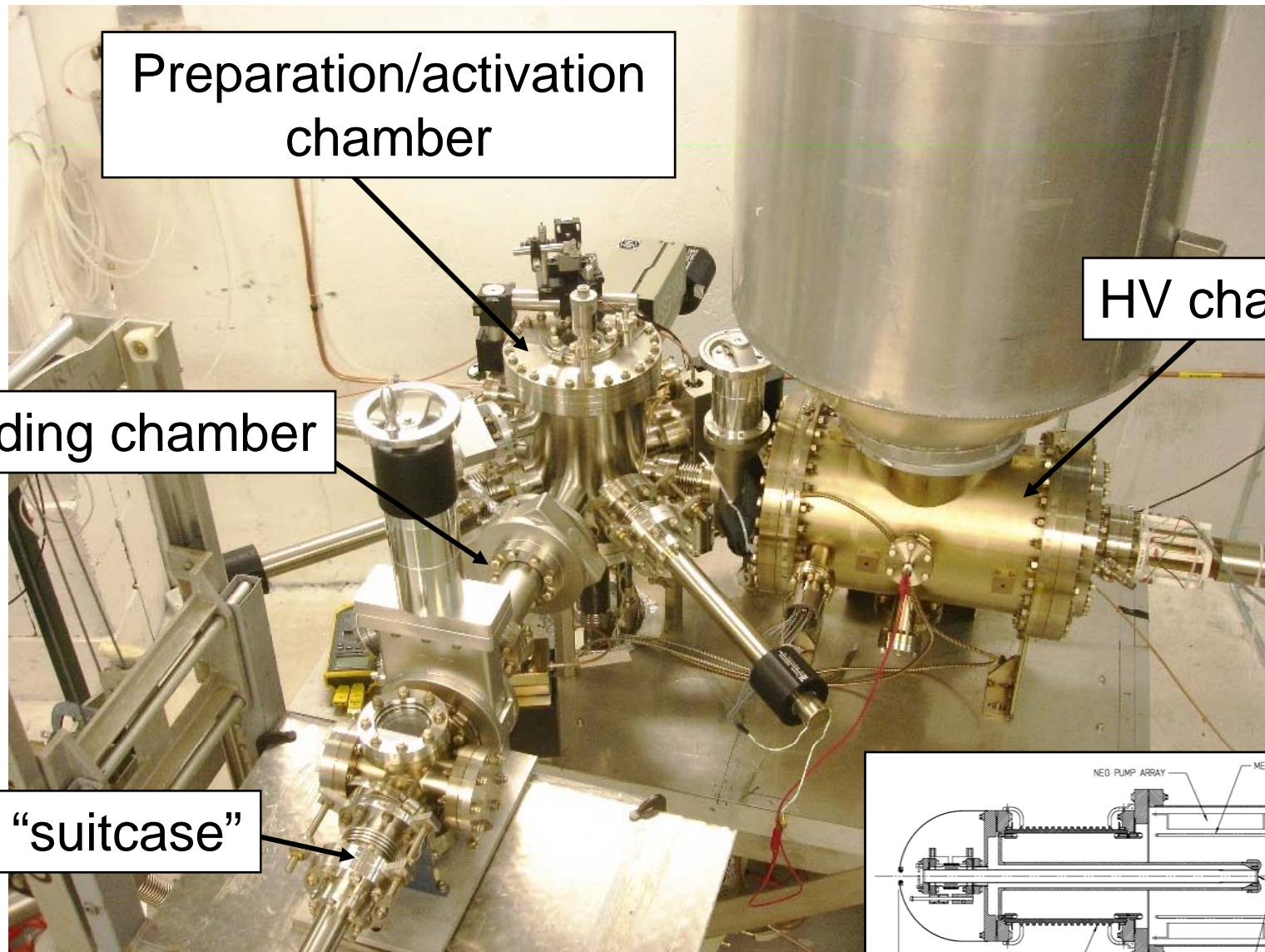


# NEG Coating



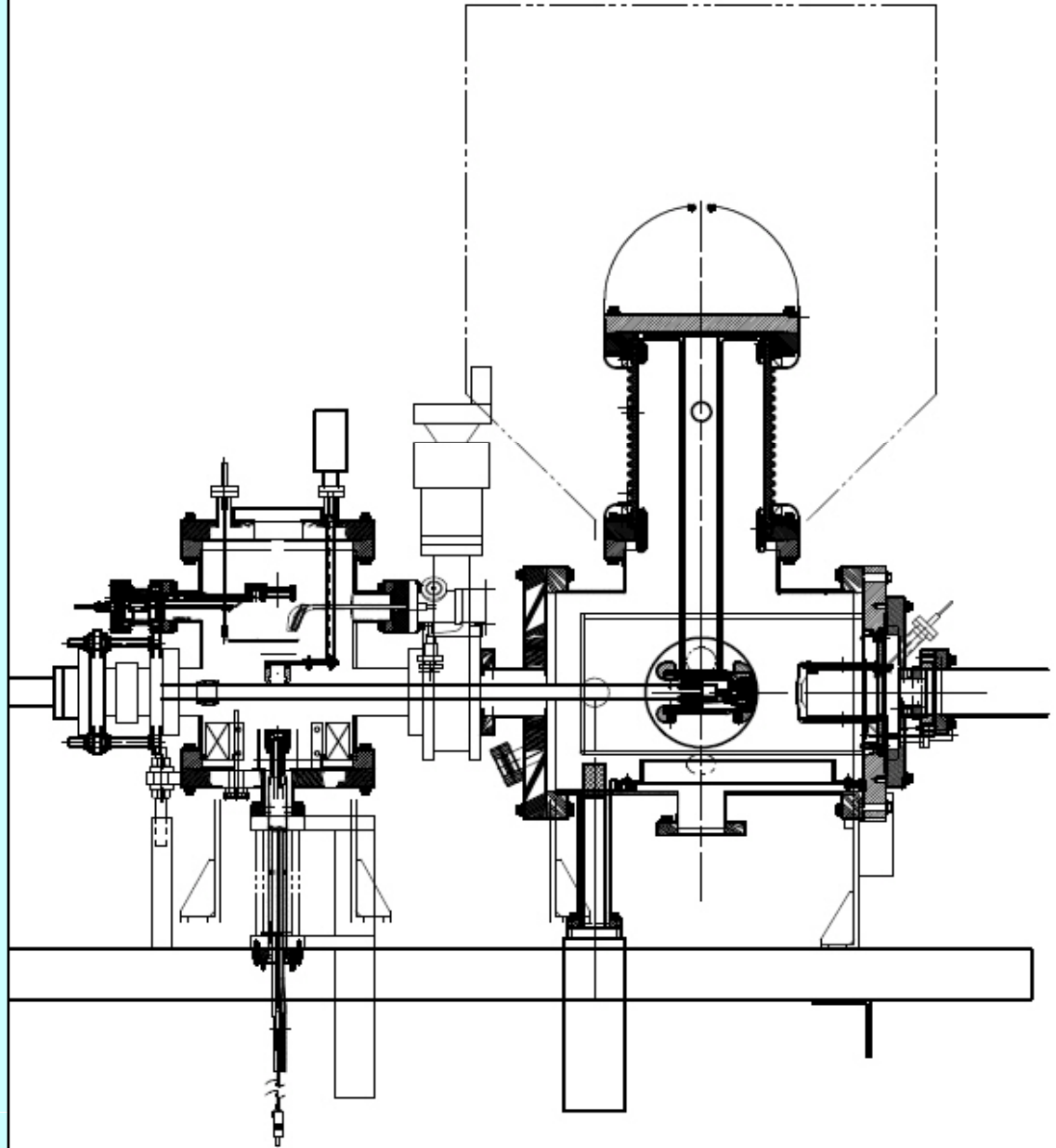
NEG coating turns a gas source into a pump  
~0.02 L/s·cm<sup>2</sup> : Modest pump speed can be improved

# New CEBAF load-locked gun



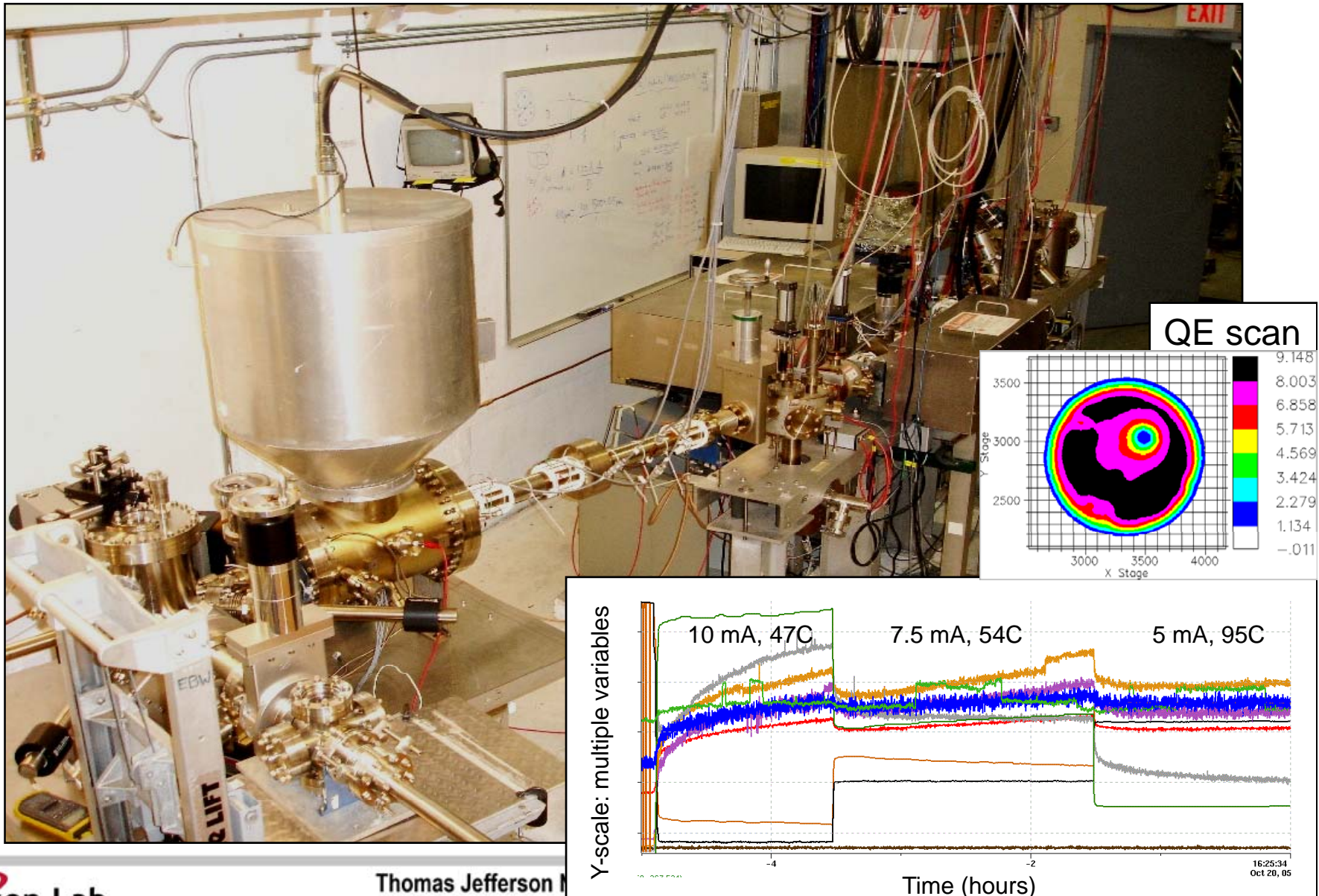
## Key Features:

- Smaller surface area
- Electropolished and vacuum fired to limit outgassing
- NEG-coated
- Never vented
- Multiple pucks (8 hours to heat/activate new sample)
- Suitcase for installing new photocathodes (one day to replace all pucks)
- Mask to limit active area, no more anodizing





# Load Locked Gun and Test Beamline

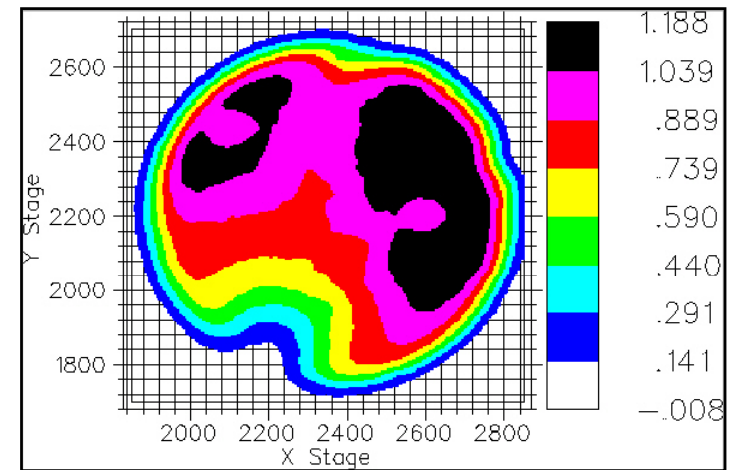


# 1mA from High Polarization Photocathode\*

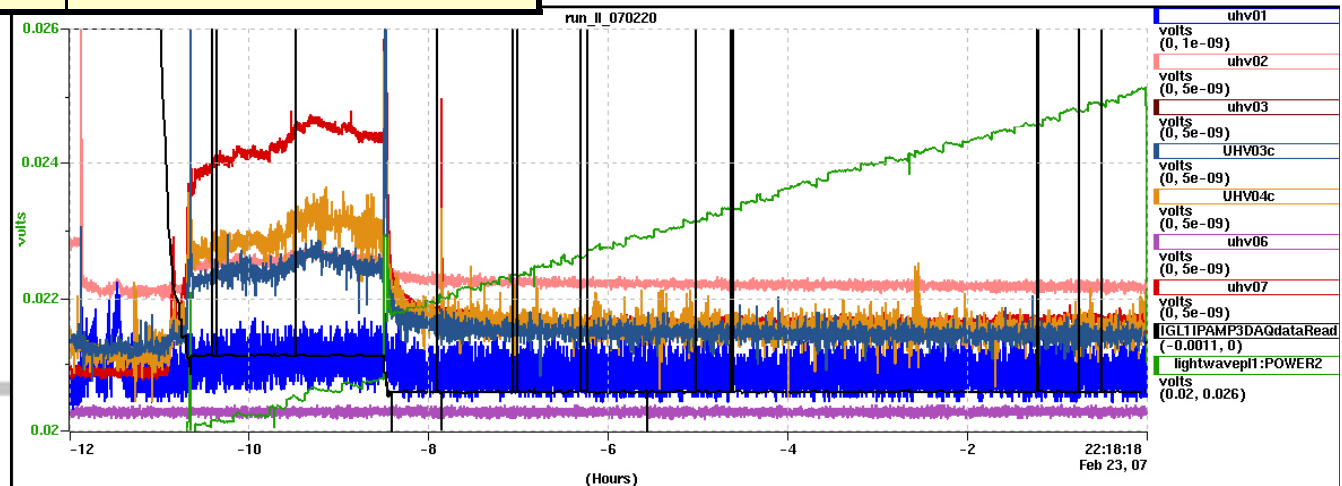
| Parameter         | Value                  |
|-------------------|------------------------|
| Laser Rep Rate    | 499 MHz                |
| Laser Pulselength | 30 ps                  |
| Wavelength        | 780 nm                 |
| Laser Spot Size   | 450 μm                 |
| Current           | 1 mA                   |
| Duration          | 8.25 hr                |
| Charge            | 30.3 C                 |
| Lifetime          | 210 C                  |
| Charge Lifetime   | 160 kC/cm <sup>2</sup> |

\* Note: did not actually measure polarization

High Initial QE



Vacuum signals  
Laser Power  
Beam Current



# Vacuum R&D Summary

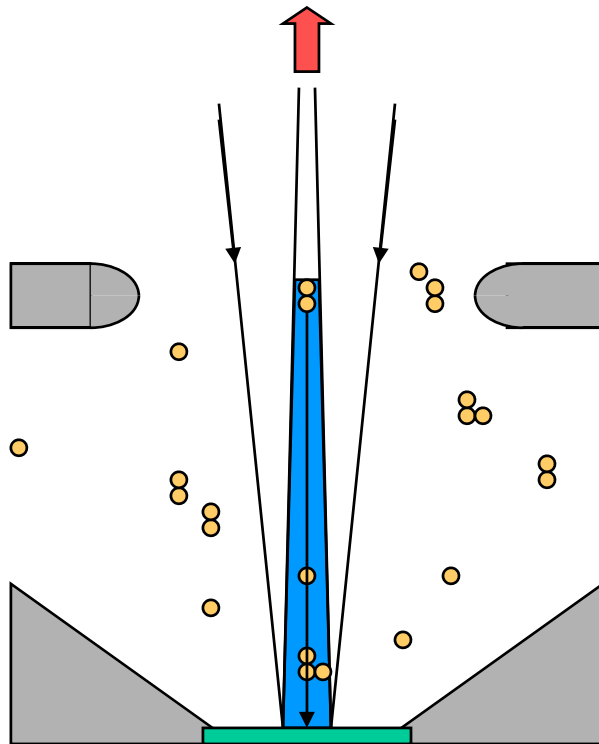
---

- Limit outgassing via high temperature 400°C bakeout
  - Can chamber be vented and still maintain low outgassing rate following 150°C, 250°C bake?
- Construct gauge that can accurately measure pressure below  $1 \times 10^{-11}$  Torr (modified Helmer gauge)
  - STTR proposal?
- Improve NEG coating process, to boost pump speed per unit area.
  - 0.02 L/s·cm<sup>2</sup> versus 1 L/s·cm<sup>2</sup> reported in literature

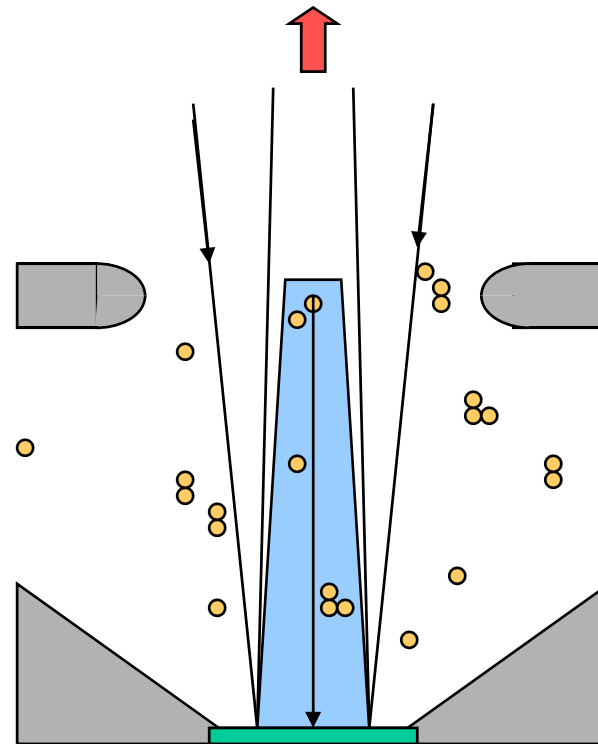
# Improve Lifetime with Larger Laser Spot?

(Best Solution – Improve Vacuum, but not easy)

Bigger laser spot, same # electrons, same # ions



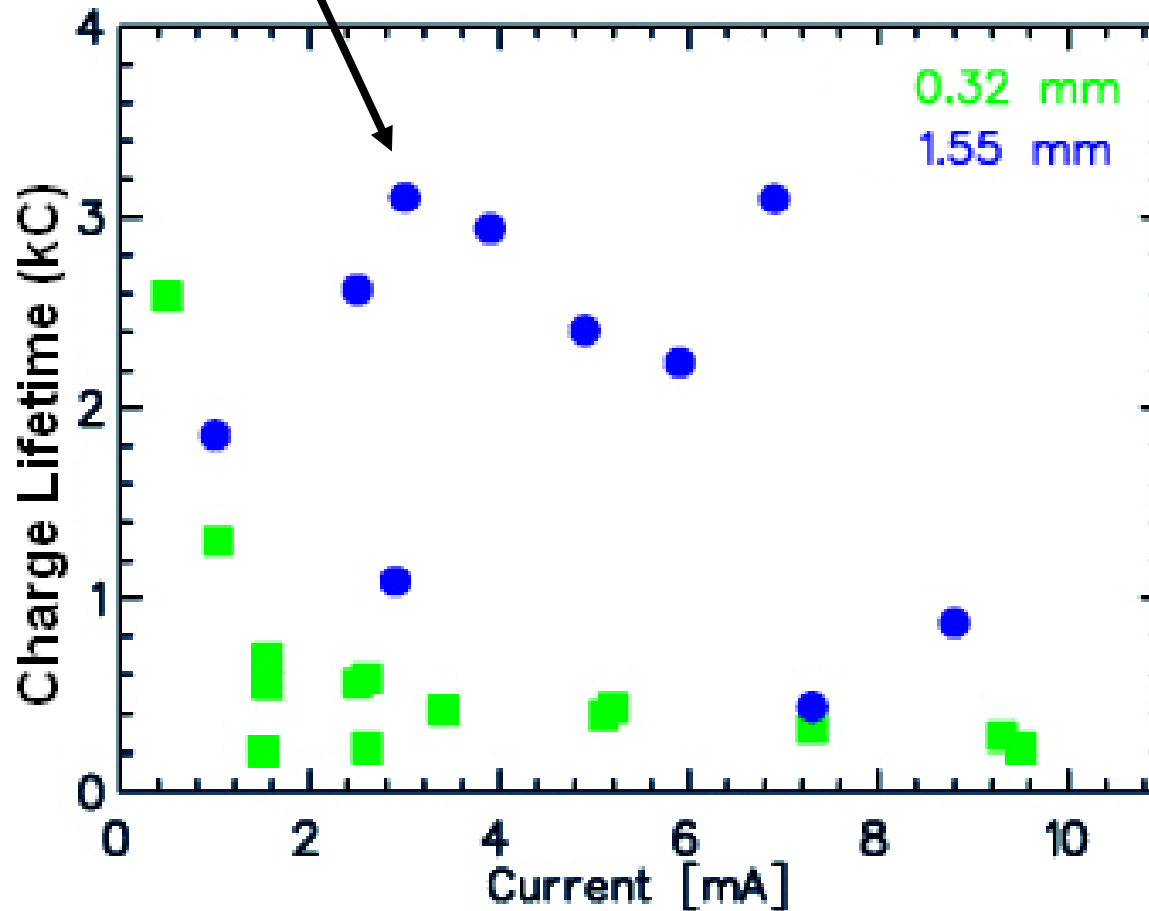
Ionized residual gas strikes photocathode



Ion damage distributed over larger area

# Lifetime with Large/Small Laser Spots

Tough to measure large Coulomb lifetimes with only 100-200 C runs!



Factor of 5 to 10 improvement with larger laser spot size

Expectation:

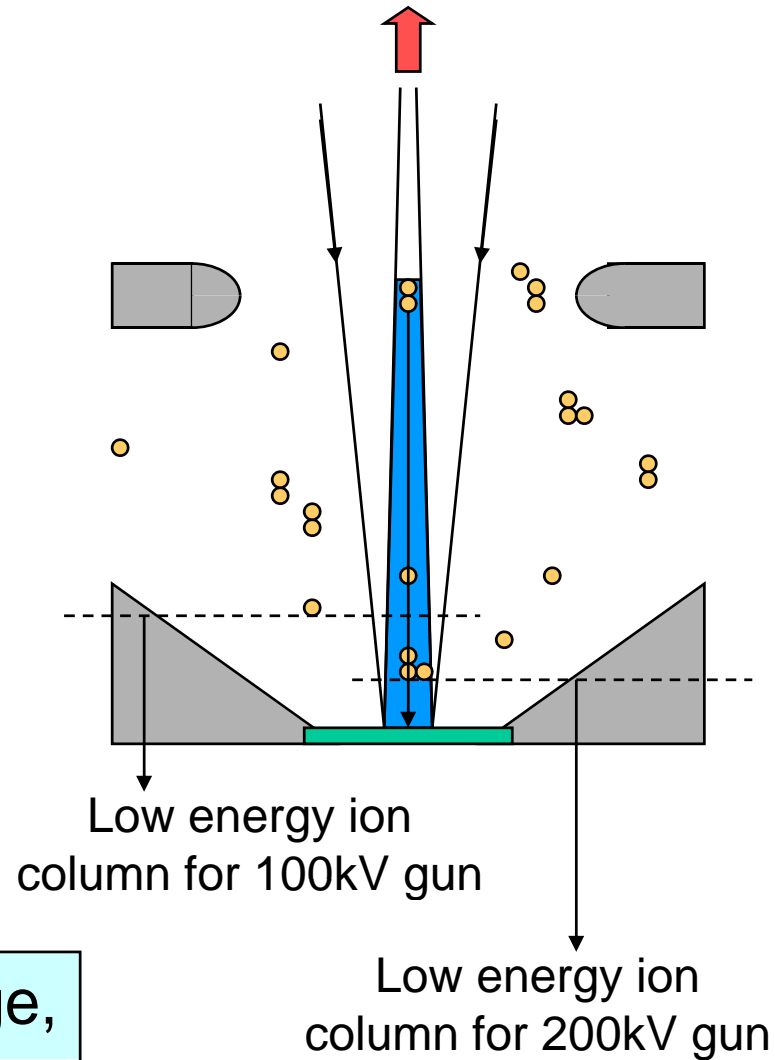
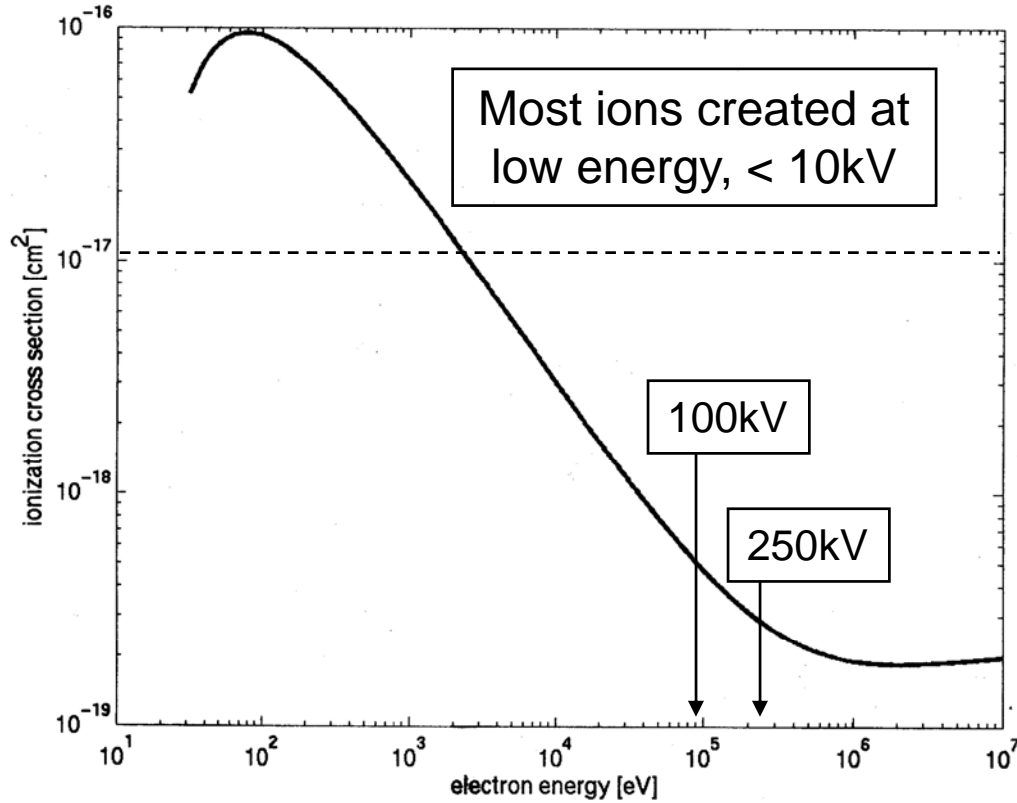
$$\left[ \frac{1500}{350} \right]^2 \approx 18$$

"Further Measurements of Photocathode Operational Lifetime at Beam Current > 1mA using an Improved 100 kV DC High Voltage GaAs Photogun," J. Grames, et al., Proceedings Polarized Electron Source Workshop, SPIN06, Tokyo, Japan



# Topic #2: Increasing Gun Voltage

Ionization cross section for H<sub>2</sub>



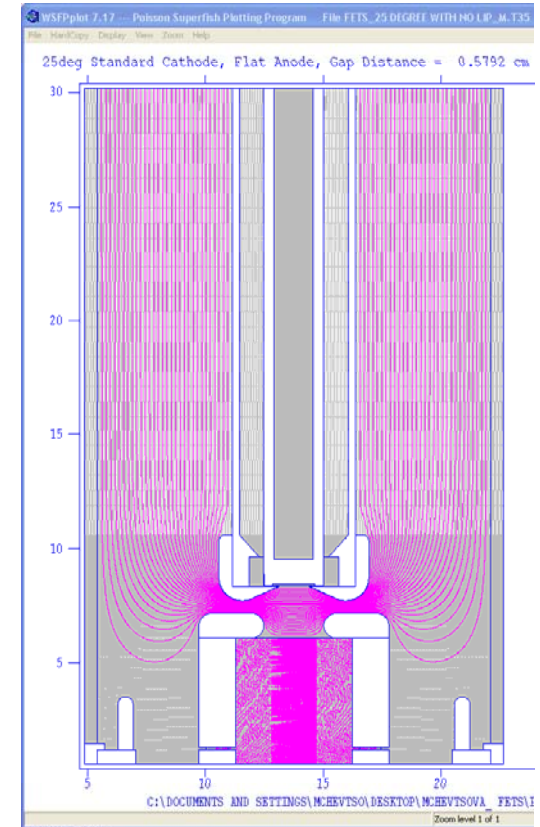
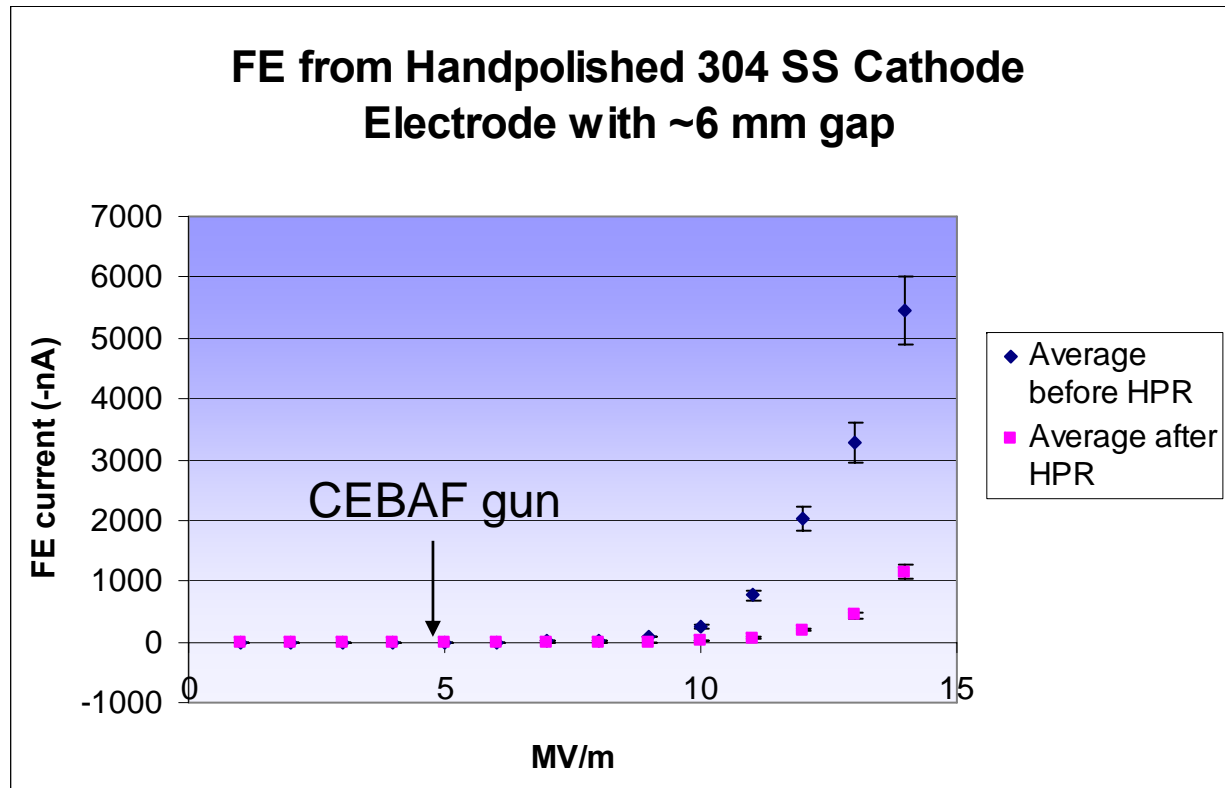
Hypothesis: Double the gun voltage, halve the # of “bad” ions, improve lifetime by 2

# Must Eliminate Field Emission

Cornell Technique, high pressure rinsing (B. Dunham ERL07)

Recent tests at JLab with shaped electrodes support Cornell results

Work of M. Chetsova K. Surles-Law



# High Voltage R&D Summary

---

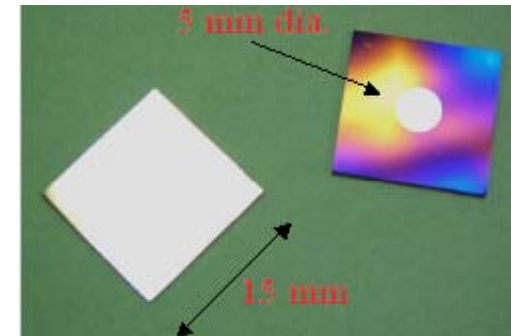
- Field Emission reduction via high pressure rinsing, and if necessary, using coatings
- Reduce complexity, cost and size of ceramic insulators. Exploit medical x-ray source technology
- Lifetime studies at injector test cave using duplicate load locked gun: observe improved lifetime at higher gun voltage
- Other reasons to increase gun voltage....

## Topic #3: Cathode/Anode Design

---

We learned at CEBAF that it is extremely important to manage ALL of the extracted beam

- Anodized edge: beam from outside 5 mm active area can hit beampipe walls, degrade vacuum, reduce operating lifetime



A better way for ILC?

Suggest multivariate optimization of:

- Cathode/anode optic
- First few meters of beamline, including SHB

# Goals of Multivariate Optimization

---

- Create cathode/anode optic with small aberration across large photocathode active area, with very little beam loss. What to optimize?
  - Size of cathode electrode diameter, size of photocathode active area
  - Size of laser beam: lowest possible current density but with adequate emittance
  - Cathode/anode shape for adequate focusing
  - Cathode voltage/gradient: higher voltage to reduce space charge and provide possibility of extracting higher peak current with more narrow laser pulsewidth, to reduce SHB requirements

# JLab-ILC Polarized e-Source R&D

---

- Vacuum R&D on-going
- Lifetime measurements at high current and 225kV will begin soon
- Graduate student to learn technique of multivariate optimization
- ..
- ..
- ..
- Begin scaling/modifying CEBAF load lock gun design for ILC parameters
- **Jlab vested interest in ILC gun program – push gun voltage**